Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination
10/520,885	BEYER ET AL.
Examiner	Art Unit
HIEU T. VO	3747

	SEARCHED				
Class	Subclass	Date	Examiner		
101	114 112 102 115 99	3/6/2006	VH		
123	478 479 494	3/6/2006	VH		
73	117.3 116	3/6/2006	VH		
73	118.1	3/6/2006	VH		

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
<u> </u>			

SEARC (INCLUDING SE	SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR		
EAST	3/6/2006	VH		